

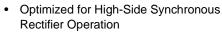
N-Channel 20V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^a	Q _g (Typ.)		
20	0.012 at V _{GS} = 10 V	12	6.1 nC		
20	0.015 at V _{GS} = 4.5 V	11	6.1 IIC		

SO-8

FEATURES

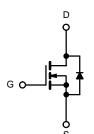
- · Halogen-free
- TrenchFET® Power MOSFET



- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Notebook CPU Core
 - High-Side Switch



N-Channel MOSFET

Unit

Limit

G 4 5	D		
Top View			
ABSOLUTE MAXIMUM RATING	S T _A = 25 °C, unles	ss otherwise n	oted
Parameter		Symbol	
Drain-Source Voltage	V _{DS}		
Gate-Source Voltage		V_{GS}	
	T _C = 25 °C		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C	<u></u>	
Continuous Diam Current (1) = 150 C)	T _Δ = 25 °C	I _D	

Drain-Source Voltage	V_{DS}	20	V		
Gate-Source Voltage	V_{GS}	± 16] v		
	T _C = 25 °C		12		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	l _D	11		
Continuous Diain Current (1) = 130 C)	T _A = 25 °C		10 ^{b, c}		
	T _A = 70 °C		8 ^{b, c}	A	
Pulsed Drain Current	I _{DM}	47	7		
Continuous Source-Drain Diode Current	T _C = 25 °C	- I _S	3.7		
Continuous Source-Drain Diode Current	$T_A = 25 ^{\circ}C$		2.0 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	20		
Avalanche Energy	L = 0.1 IIII1	E _{AS}	21	mJ	
	T _C = 25 °C		4.1	W	
Maximum Power Dissipation	$T_C = 70 ^{\circ}C$	P _D	2.5		
Maximum Fower Dissipation	T _A = 25 °C	' ^D	2.2 ^{b, c}		
	T _A = 70 °C] [1.3 ^{b, c}		
Operating Junction and Storage Temperature Ra	T_{l}, T_{sta}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	39	55	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	25	29	C/VV

Notes:

- a. Base on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.

1

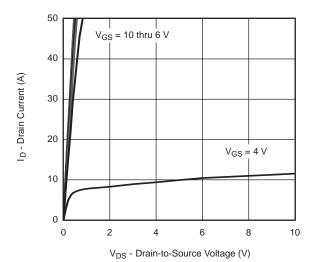


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static		,			•		
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	20			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		26		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	ι _D = 250 μΑ		- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Cata Valta na Duain Comunit		V _{DS} = 20 V, V _{GS} = 0 V			1	μА	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 20V$, $V_{GS} = 0$ V, $T_{J} = 55$ °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
	_	V _{GS} = 10 V, I _D = 10 A		0.012			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 9 A		0.015		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 10 A		50		S	
Dynamic ^b							
Input Capacitance	C _{iss}			800			
Output Capacitance	C _{oss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		165		pF	
Reverse Transfer Capacitance	C _{rss}			73			
<u> </u>	Qg	V _{DS} = 10 V, V _{GS} = 10 V, I _D = 10 A		15	23	nC	
Total Gate Charge				6.8	10.2		
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5			
Gate-Drain Charge	Q_{gd}			2.3			
Gate Resistance	R_g	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	23		
Rise Time	t _r	V_{DD} = 10 V, R_L = 1.4 Ω		12	16		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22		
Fall Time	t _f			10	18		
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	V_{DD} = 10 V, R_L = 1.4 Ω		10	20]	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	22		
Fall Time	t _f			8	15	1	
Drain-Source Body Diode Characterist	ics			•	•	•	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			10		
Pulse Diode Forward Current ^a	I _{SM}				50	A	
Body Diode Voltage	V_{SD}	I _S = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 9 A, dI/dt = 100 A/μs, T _J = 25 °C		6	12	nC	
Reverse Recovery Fall Time	t _a	i _F = θ A, αί/αι = 100 Α/μs, 1 _J = 25 °C		8			
Reverse Recovery Rise Time	t _b			7		ns	

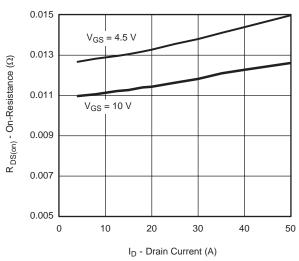
- a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

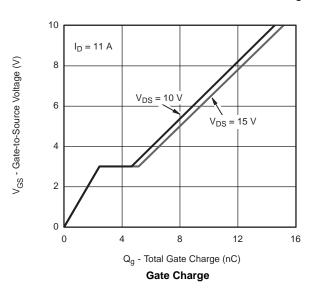


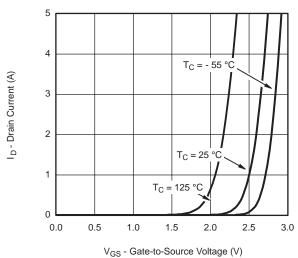


Output Characteristics

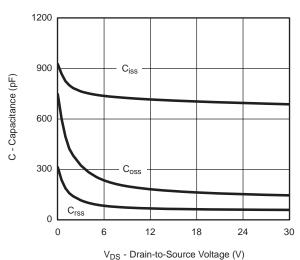


On-Resistance vs. Drain Current and Gate Voltage



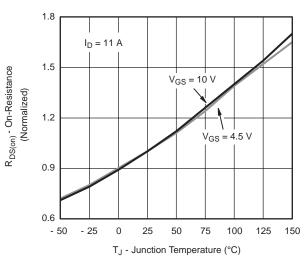


Transfer Characteristics



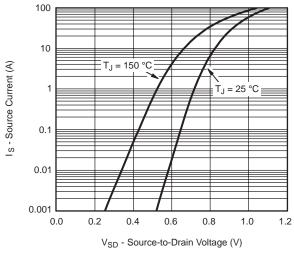
- Drain-to-Source voltage

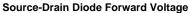
Capacitance

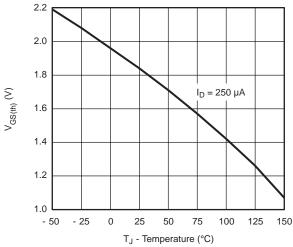


On-Resistance vs. Junction Temperature

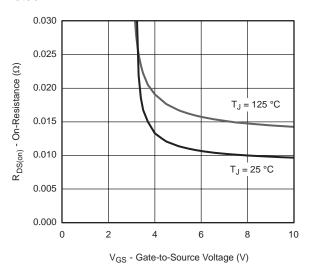




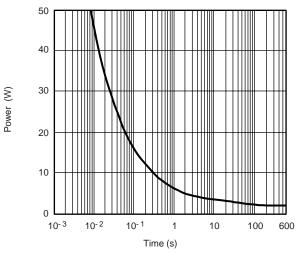




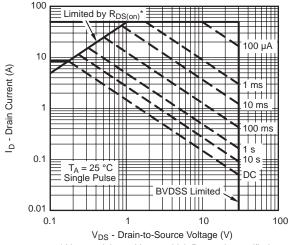
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



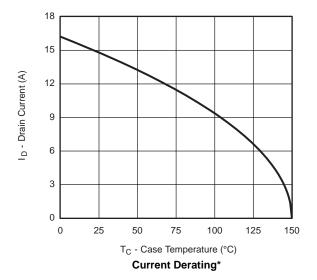
Single Pulse Power, Junction-to-Ambient

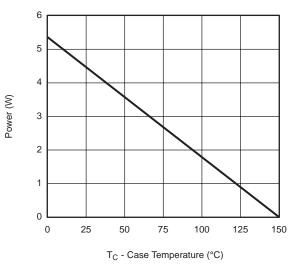


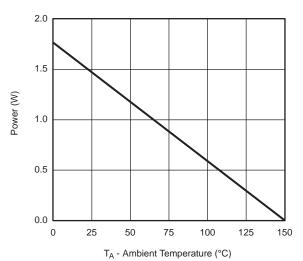
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient







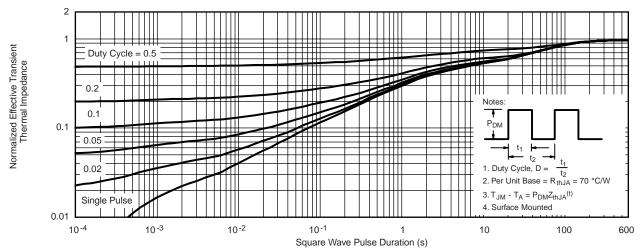


Power Derating, Junction-to-Foot

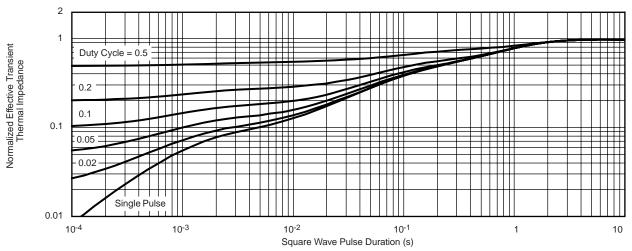
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





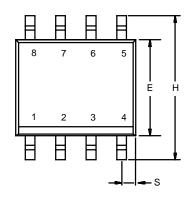
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD







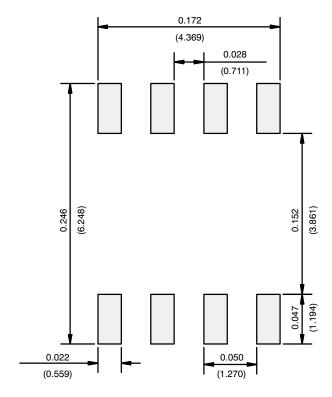
	MILLIMETERS		INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
Е	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sep-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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9